



Docket No.: 50090-478

PATENT

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Application of : Customer Number: 20277  
Yukikazu MATSUO, et al. : Confirmation Number: 5606  
Serial No.: 10/084,338 : Group Art Unit: 2133  
Filed: February 28, 2002 : Examiner: James C. Kerveros  
For: TESTING DEVICE OF SEMICONDUCTOR INTEGRATED CIRCUIT AND  
TEST METHOD THEREFOR

**RECEIVED**

**OCT 01 2004**

**Technology Center 2100**

**AMENDMENT**

Mail Stop Amendment  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

In response to the Office Action of July 2, 2004, please amend the above-identified application as follows:

**Amendments to the Specification** begin on page 2 of this paper.

**Amendments to the Claims** are reflected in the listing of claims which begins on page 3 of this paper.

**Remarks** begin on page 7 of this paper.